

**Users Meeting Workshop  
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***Amorphous Silicon  
based matrix detectors  
for X-ray Imaging***



# OUTLINE

- X-ray imaging (medical): Challenges, needs, requirements ...
- **Flat Panel Detector [FPD] basis.**
  - Interaction layers ("direct/indirect" conversion)
  - Signal Storage
  - Readout schematics
  - Examples of structures
- Products characteristics
- Limitations for a-Si based FPDs.

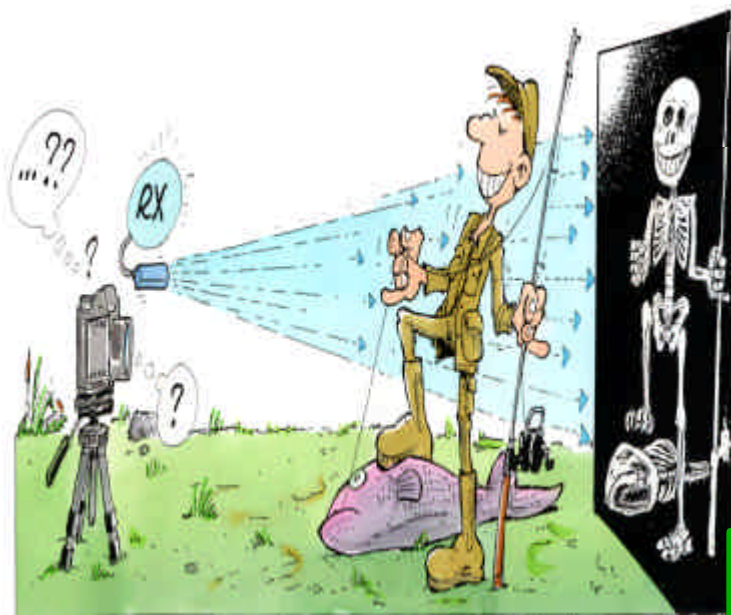


# I- The Challenges In X-ray Imaging

- 1- **Replace gradually the film-screen** systems with a wholly electronic, digital detector for static medical imaging. **Reduce costs and dose.**
- 2- **Replace the XRII-camera** with a digital detector also offering radiographic quality on isolated images.
- 3- Address other specific applications (NDT, scientific ...)

# Need of large area detectors

- X-ray images are formed as shadows (Projections) of the interior of the body/object.



- Not practical/possible to focus X-rays,
- A practical difficulty in making an x-ray detector is the **need to image a large area** (solutions: 1D detector + scanning; optical coupling "phosphor +lens+CCD ..."; photostimulable phosphor; ...)
- A full size detector is needed.

- Amorphous silicon flat-panel active matrix array, originally developed for **computer displays** is the only technology able to meet this demand.

# Compared requirements for radiography and fluoroscopy

	General radiography	Mammography	Fluoroscopy
Size	> 40 x 40 cm	>18 x 24 cm	>30 x 30 cm
Pixel size	~ 150 $\mu\text{m}$	60-100 $\mu\text{m}$	200-400 $\mu\text{m}$
Typical nb of incid.X/pel	~1000	~5000	~10
Corresponding dose	2.5 $\mu\text{Gy}$	100 $\mu\text{Gy}$	25 nGy
Energy range	30-120 keV	~20 keV	30-120 keV
Input equiv. noise	< 5 X quanta	< 5 X quanta	< 1 X quantum
Dynamic range	12 bit	12 bit	12 bit
Readout time	1-5 s	1-5 s	~30 ms (30fps)

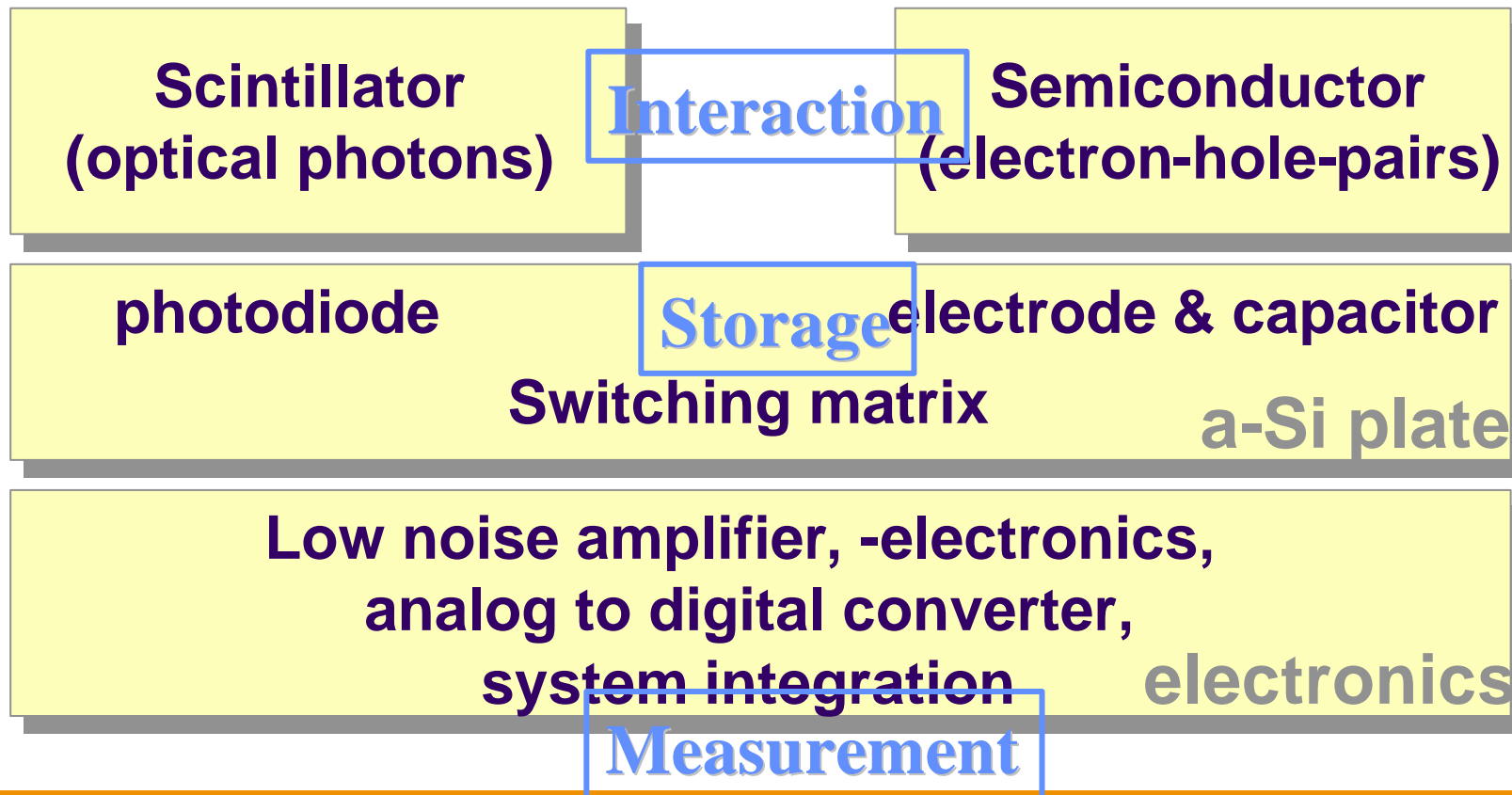
Table I. Summary of the main requirements for medical X-ray imaging.

**At 50 to 70 keV: 1 $\mu\text{Gy}$  ~ 400 to 500 X photons per pixel of ~150x150 $\mu\text{m}^2$**

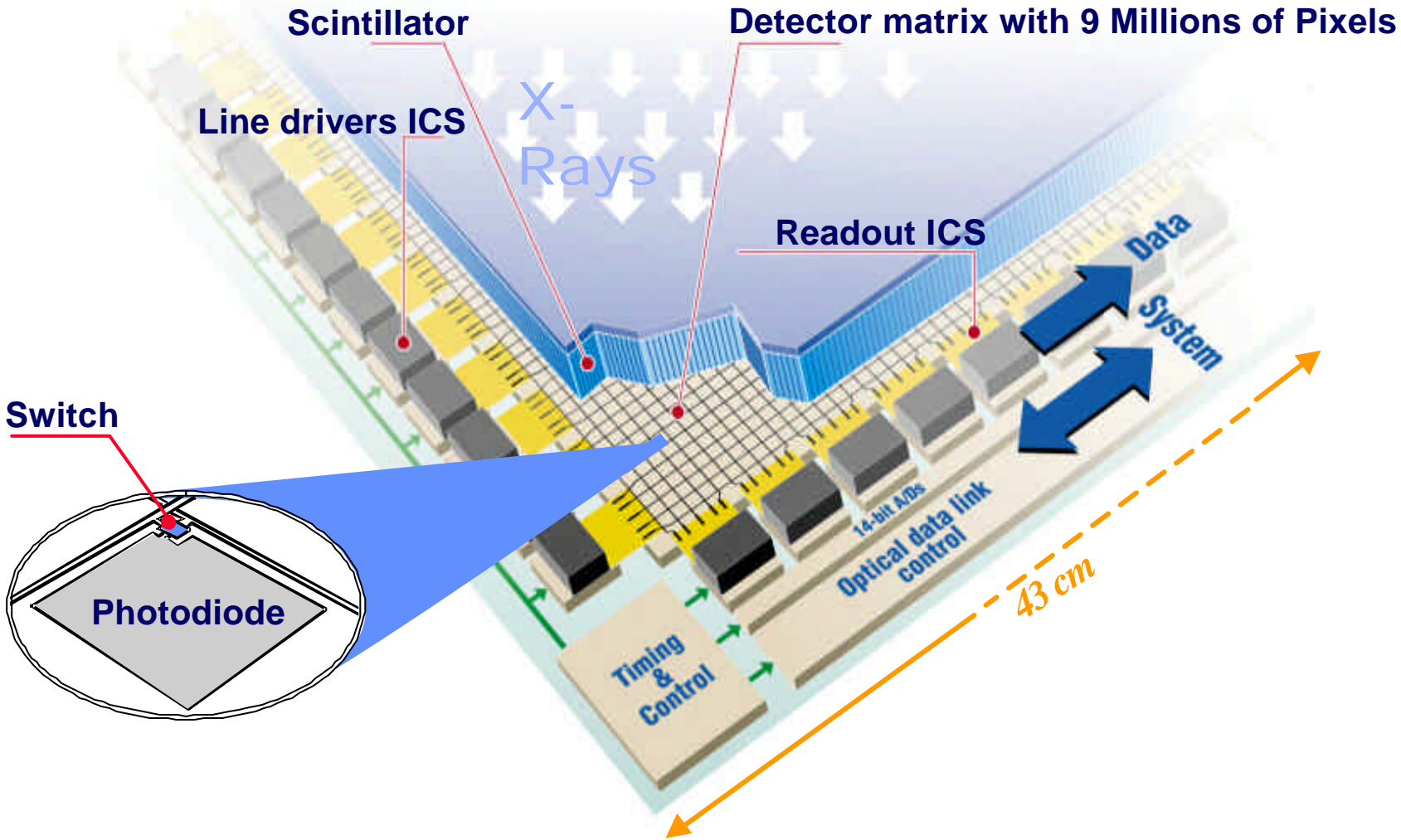
## II- FPD Basis

- The basis of **Flat Panel Detector** (FPD) = coupling traditional x-ray detection material (scintillators or photoconductors) with a large area active-matrix readout structure.
- **Creation of a x-ray image can be divided into 3 major steps:**
  - x-rays **Interaction** with a detection medium → detectable signal.
  - Signal **Storage**
  - Stored signal **Measurement**
- In digital imaging systems the incident image must be **sampled**: in the **spatial** (pixels) and **intensity** (gray levels or bits) **dimensions**.

# There exists two approaches opto-direct ('indirect') and electro direct



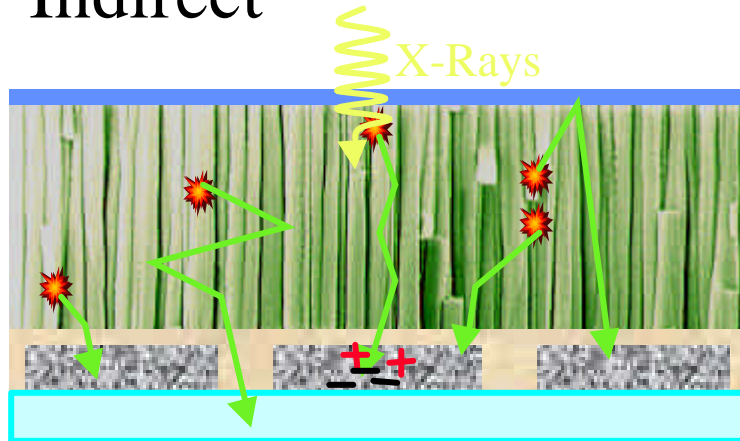
# Technical stack



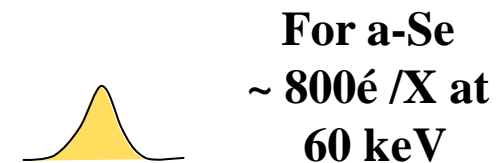
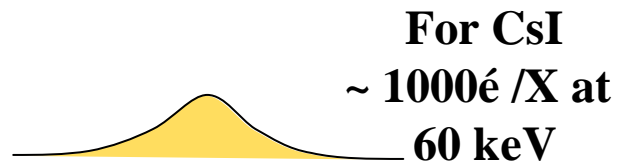
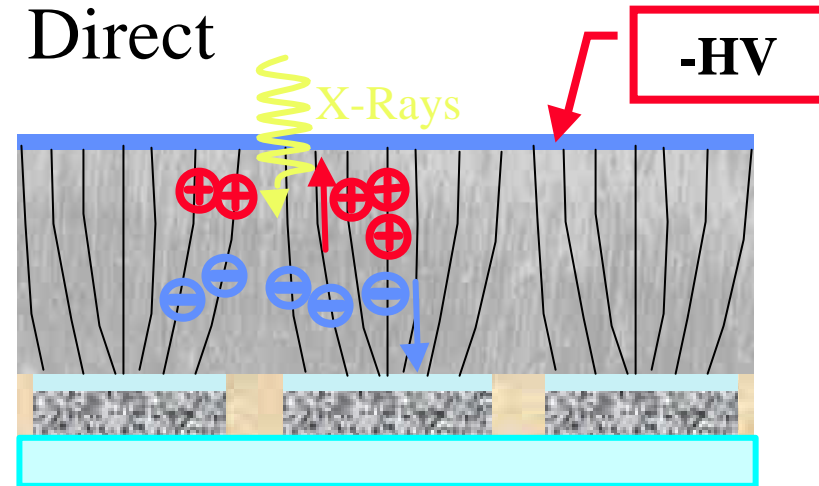


## II-1 - Interaction: Direct vs. Indirect approaches

Indirect

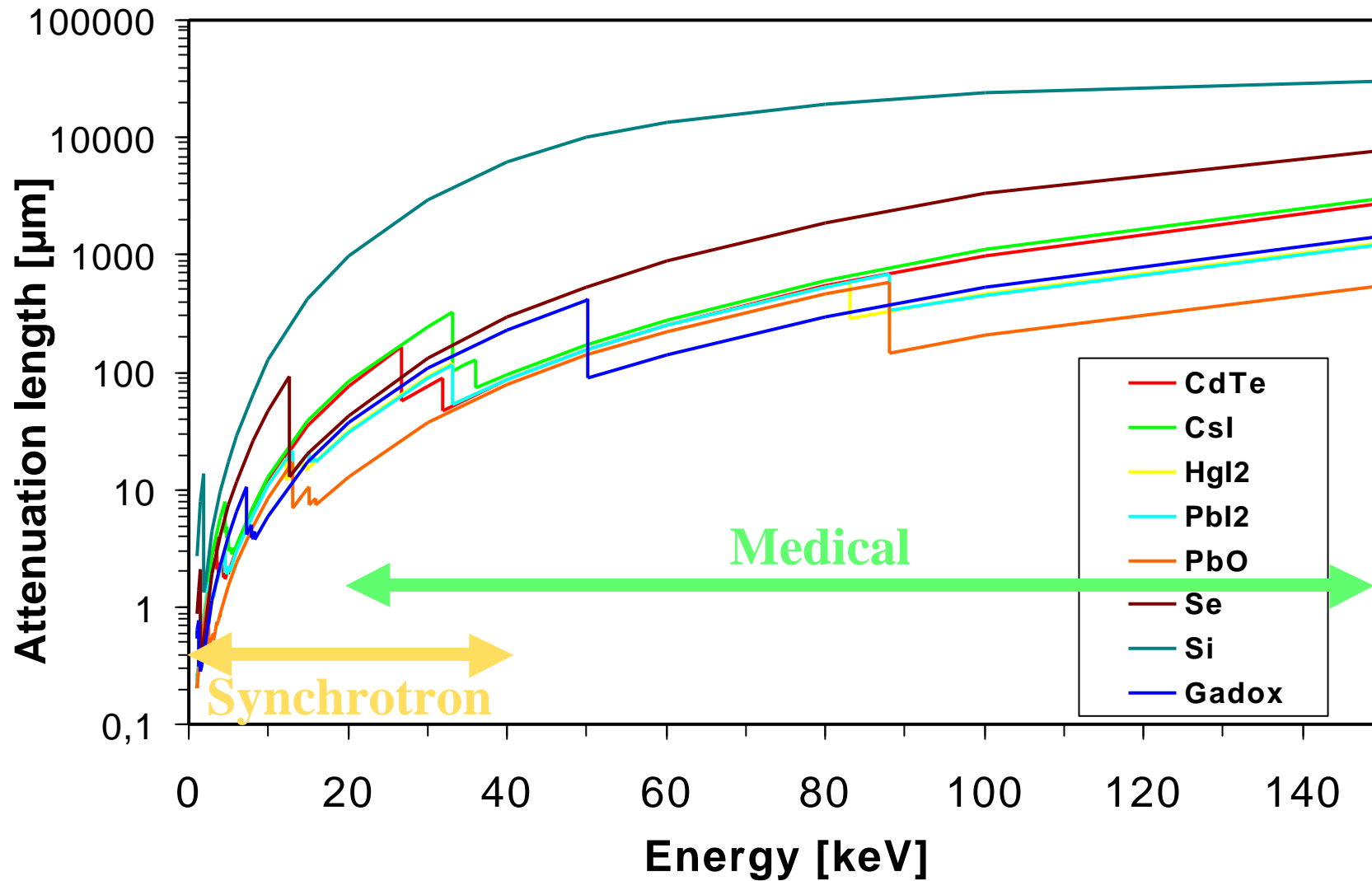


Direct



- a-Se based FPD is the only commercial available photoconductor solution
- For Direct conversion, charges carriers are driven by electrical field => good spatial resolution

# X-Ray Absorption length



# Photoconductors vs. Scintillators (1)

- **Resolution losses (blurring effects) common to all media:**
  - Geometrical (oblique x-rays) → absorption at different depths.
  - K-fluorescent x-rays
  - Others: Lubberts, statistical fluctuations ...
- **Photoconductors:**
  - Theoretically nearly perfect MTF ... at first order
  - a-Se (only available solution) is an exception to Klein's rule (e-h pair creation energy  $W_{\text{eff}} \sim 3E_g$ );  $W_{\text{eff}} \text{ high} > \sim 50 \text{ eV}$  (Klein  $\implies \sim 7 \text{ eV}$ )
  - Recrystallization problems with a-Se
  - High voltage needed ( $E > 10 \text{ V}/\mu\text{m}$ ), risk for active matrix.
  - basic condition :  $\mu\tau E > \text{absorption length}$
  - Low Z for a-Se (34) require large thickness layers for high quantum efficiency at energies  $\sim 100 \text{ keV}$  (diagnostic energies).
  - Other materials are under investigation (CdTe, HgI<sub>2</sub>, PbI<sub>2</sub>, PbO, TlBr, ...)
  - **No (?) Dynamic (30 Hz) product available !!**

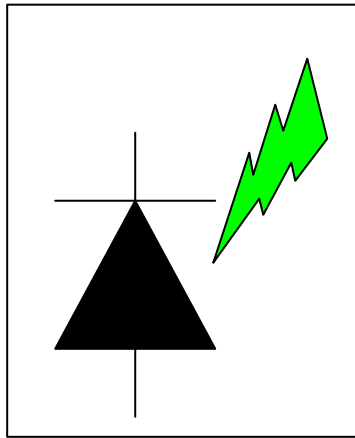
## Photoconductors vs. Scintillators (2)

- **Scintillators:**

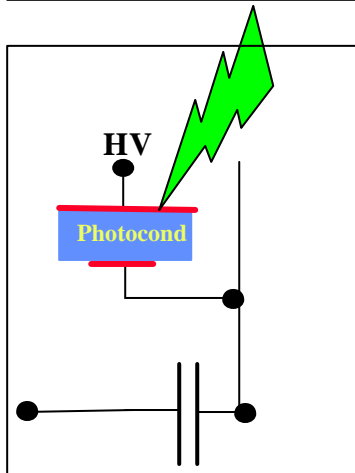
- Many materials exists ( $\text{CaWO}_4$ ,  $\text{Gd}_2\text{O}_2\text{S:Tb}$ ;  $\text{CsI:Na}$ ;  $\text{CsI:Tl}$ ; ...),
- Physical structure can be very different.
- Main issue is the **balance between spatial resolution and X-ray detection efficiency.**
- Solution = use of a structured scintillator eg.  $\text{CsI}$  (needle).
- The type of activator impurity introduced into the layer controls the emission spectrum ( $\text{CsI:Na} \rightarrow \text{blue}$ ;  $\text{CsI:Tl} \rightarrow \text{green}$ ).
- Problems with  $\text{CsI}$ : hydroscopic
- **Dynamic products ( $\approx 30$  Hz) exists !!**

## II-2 - Signal Storage

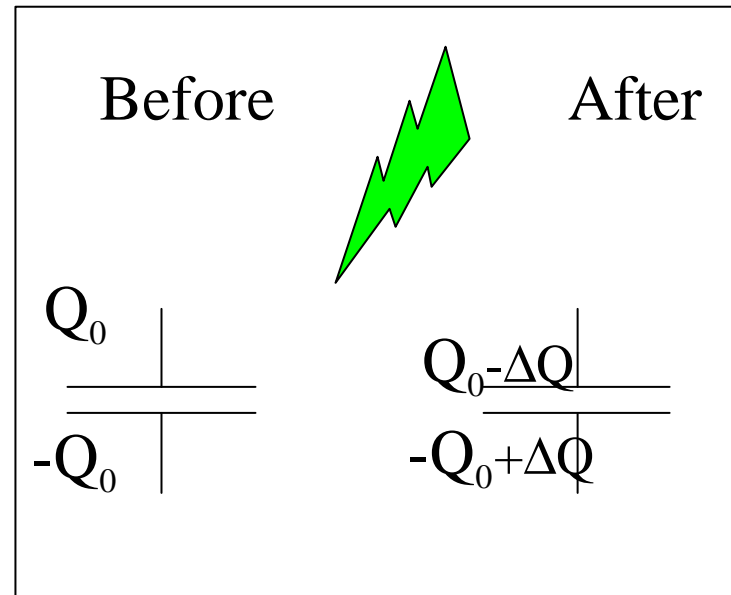
Signal (direct or indirect) generates electron-hole pairs in either photodiode or photoconductor



Indirect approach:  
Storage in photodiode



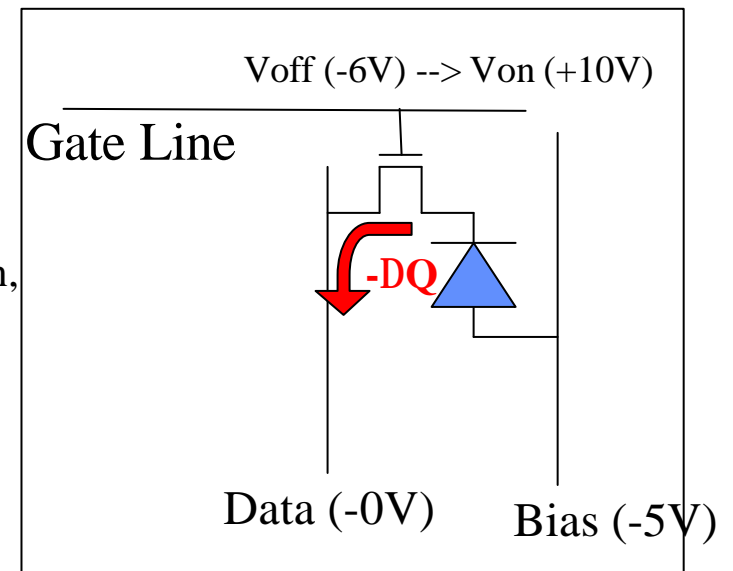
Direct approach:  
Storage in capacitor



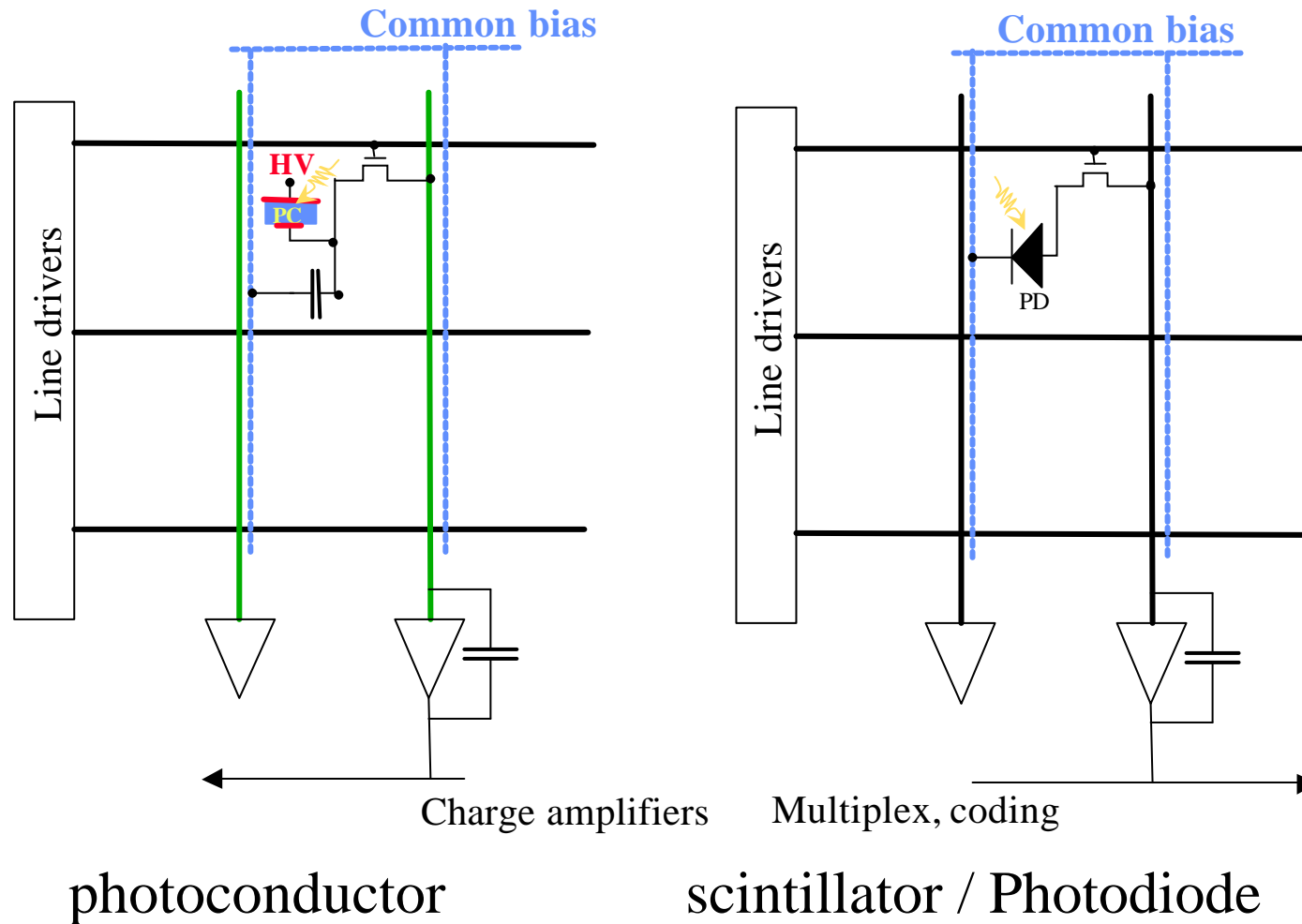
$\Delta Q$  proportional to  
incident signal

# Switching element

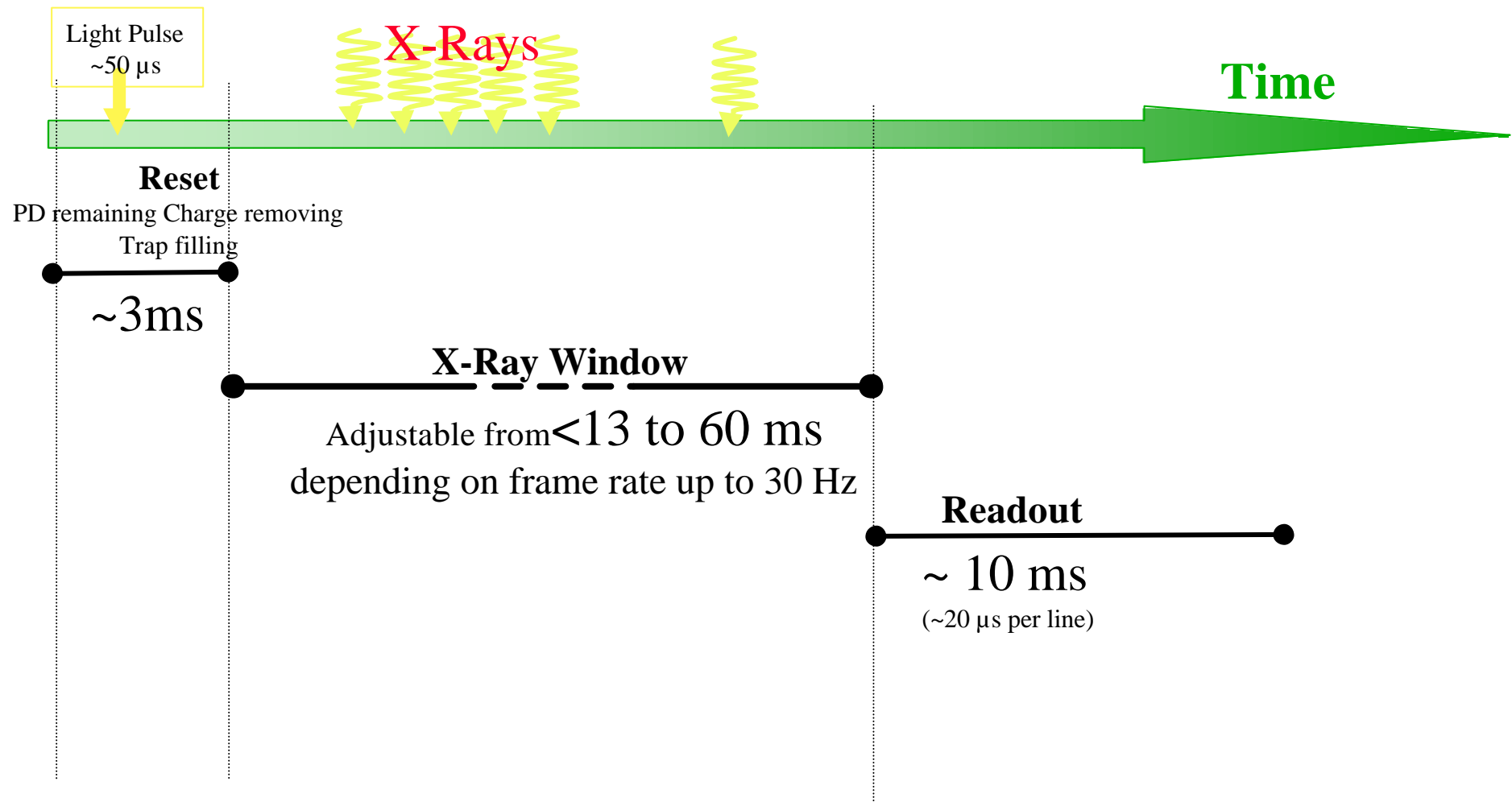
- The charge resulting from X-ray exposure is temporarily stored until it is transferred to the readout amplifier via the data column.
- Transfer is performed by a switch
- This switch is activated by an appropriate control pulse.
- Two concepts have been implemented:
  - a. **Switching Diodes.**
  - b. **TFT.**
- Properties of the switch:
  - more than 1000 switches in parallel on a data column,
  - Large dynamic range  $\Rightarrow R_{\text{off}} / R_{\text{on}} > 10^6$ .
  - $R_{\text{on}} \cdot C_{\text{pixel}} < \text{readout time}$
  - negligible noise



## II-3 - a-Si Matrix & Readout architecture

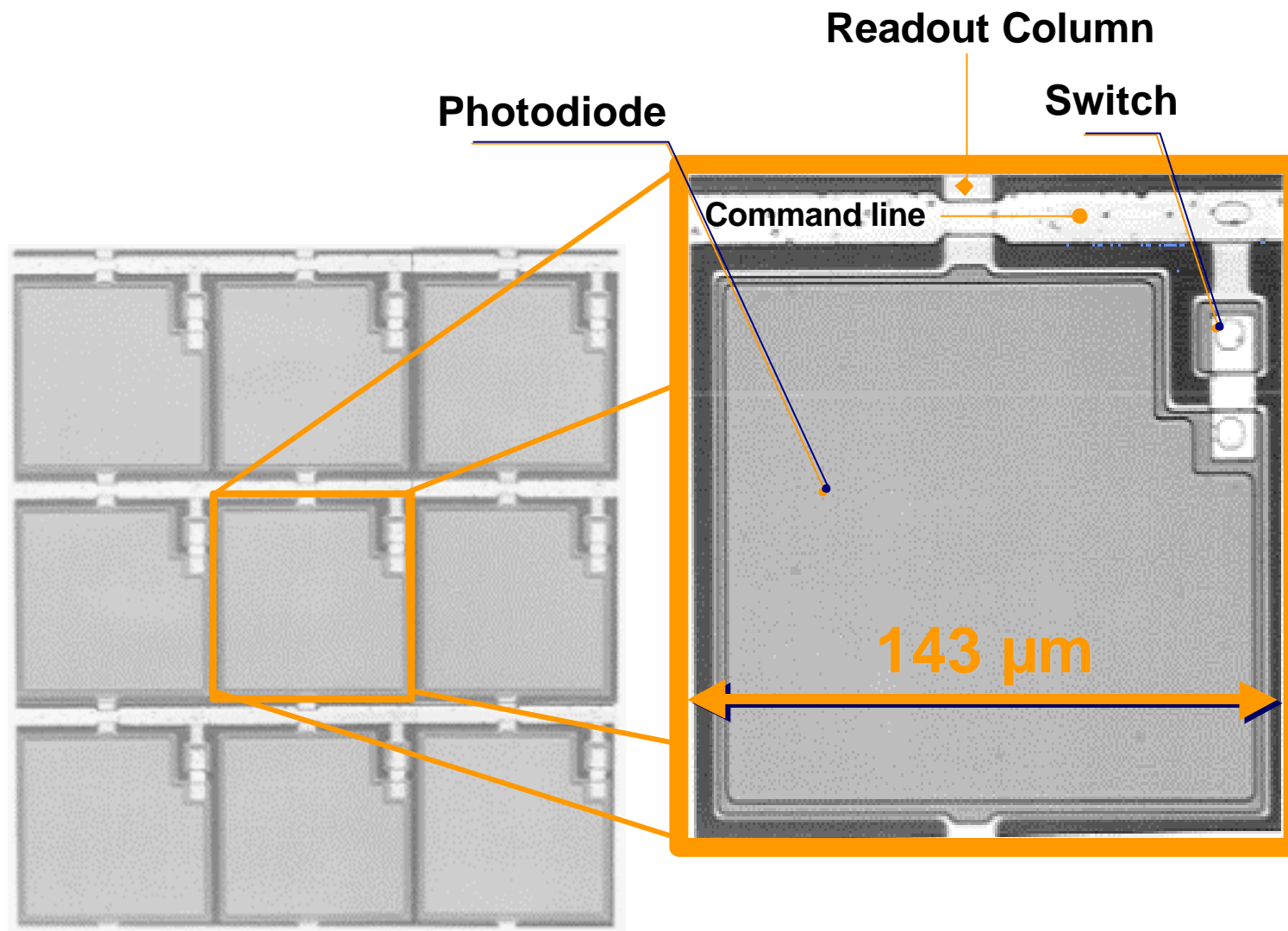


# Dynamic Imager operation



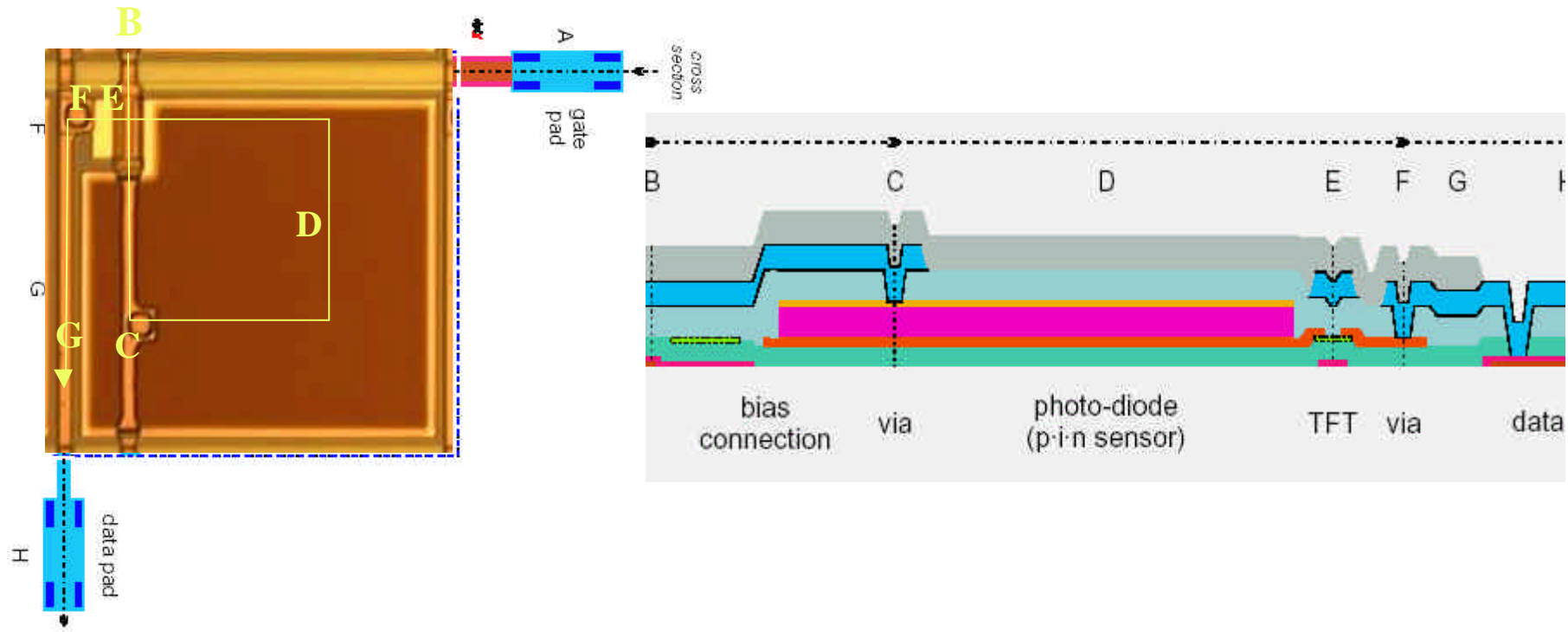


## II-4 - a-Si matrix (Double diode)



# Example of TFT a-Si Matrix Structure

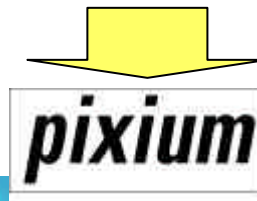
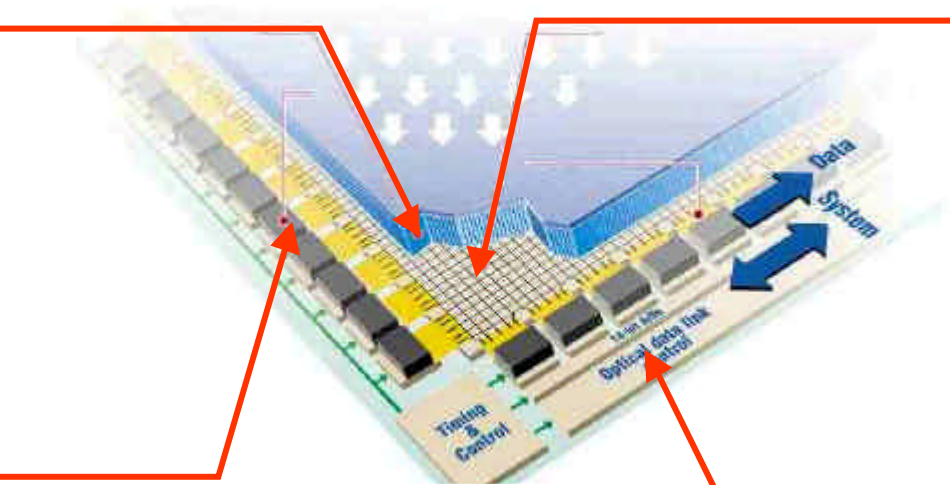
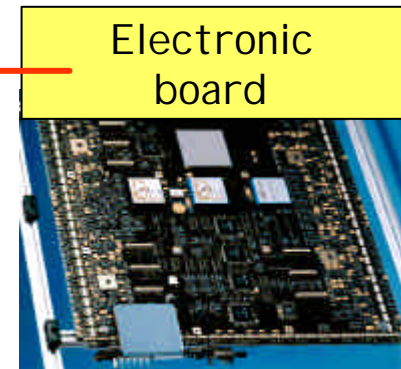
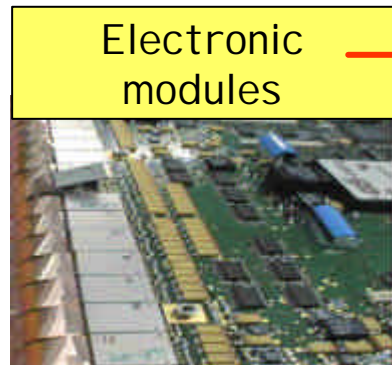
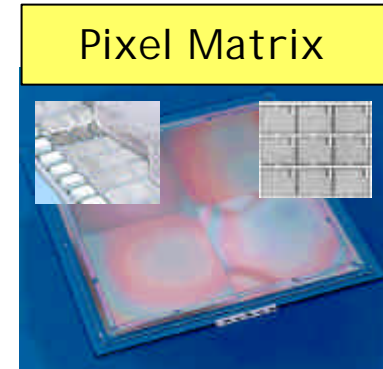
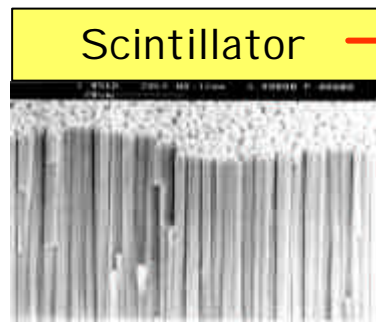
- TFT switch + Photodiode



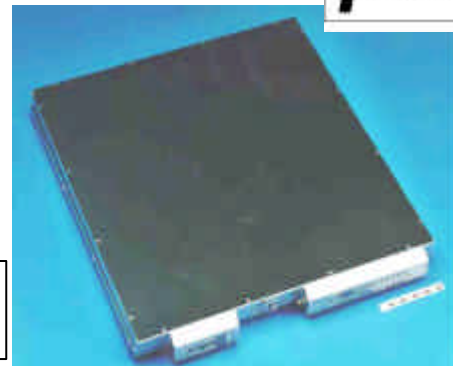
Top view

Cross section (not to scale)

# Technology



4600



4800



TRIXELL Products	Pixium 4600	Pixium 4800	Pixium 4700
Application	Graphy	Cardiology	Scopy/graphy
<b>Image Geometry</b>			<b>in Development</b>
Pixel Pitch [ $\mu\text{m}$ ]	143	184	155
X-ray sensitive array [mm x mm]	H426,3 x V432,0	176,6x176,6	~ 420 x340
Image size [pixels]	H2981 x V3021	960 x 960	~2300 x 1900
<b>Operation Mode</b>			
A/D conversion dynamic range [bits]	14	14	14
Frame Rate [Hz]	n.a.	30 (max.)	30
Time between images [ms]	> 5000	> 33	> 33
X-ray window duration [ms]	1 to 3200	13 to 60	4,5 to 5000
Image readout Time [ms]	1250	< 10	< 10 to 150
<b>Characteristics</b>			
X-ray generator voltage range [kV]	40-150	40-125	40-125
Noise equivalent dose	0,3 $\mu\text{Gy}$	1,3 nGy/fr	
System dose	0,5 to 5 $\mu\text{Gy}$	430 nGy/fr	7nGy/fr to 100nGy/fr
Maximum linear dose	60 $\mu\text{Gy}$	4,3 $\mu\text{Gy/fr}$	24 $\mu\text{Gy/fr}$
Differential non linearity (0 to Dmax)	< +/- 3%	< +/- 2%	
MTF @ 1lp/mm [%]	60	65	
MTF @ 2lp/mm [%]	DN5 35	32	30
DQE @ 0,1lp/mm [%]	2,5 & 1 $\mu\text{Gy}$ 55	65	70
DQE @ 1lp/mm [%]	2,5 & 1 $\mu\text{Gy}$ 40	58	
DQE @ 2lp/mm [%]	2,5 & 1 $\mu\text{Gy}$ 25	40	
Residual Signal (lag & memory effect) after X-Ray off			
@ 1rst frame : @ 30fr/s [%]	n.a.	< 3%	
@ 1s	n.a.	< 1%	
@ 10s	< 0,2%	< 0,2%	
@ 60s	< 0,02%	n.a.	
PC Acquisition Card	PCI 32 bits 33 MHz	PCI 64 bits 66 MHz	

# Limitations for a-Si based FPD

- Conversion layer Absorption (a-Se, Gd<sub>2</sub>O<sub>2</sub>S ...).
- Fill factor (indirect approach only ?), shrinking of pixel size difficult.
- Residual signal
  - Incomplete readout (RC constant of the switching TFT)
  - Release of trapped charge from photodiode (or photoconductor), "memory effect". (solution = light pulse to fill traps in PD (N<sub>t</sub> #  $5 \cdot 10^{15} \text{ cm}^{-3}$ )) } **Dominant**
  - scintillator "after glow"
- Leakage current (photodiode (~fA) or photoconductor), ==> small reduction of dynamic range with time
- Defects (pixels, gain differences ...)
- Electronic noise associated to line capacitance and resistance
- Integration of "pixel electronics" limited.

# CsI:Tl/a-Si is the good compromise now

- Technical reasons: **(medical)**
  - X-ray absorption, conversion efficiency, needle structure
  - a-Si sensitivity well matched to CsI emission,
  - a-Si double diode or photodiode/TFT with appropriate performance available.
- Industrial Reasons:
  - Long experience of CsI deposition
  - Mastering the technology has been achieved
  - Costs of the existing products will decrease in the future.
- Performance
  - Good in radiography, and in cardio-vascular (fluoroscopy).

46kV 3.948mAs 16.27ms

Philips



0.2128cGycm2 g

4\*1cm

Pixium 4600

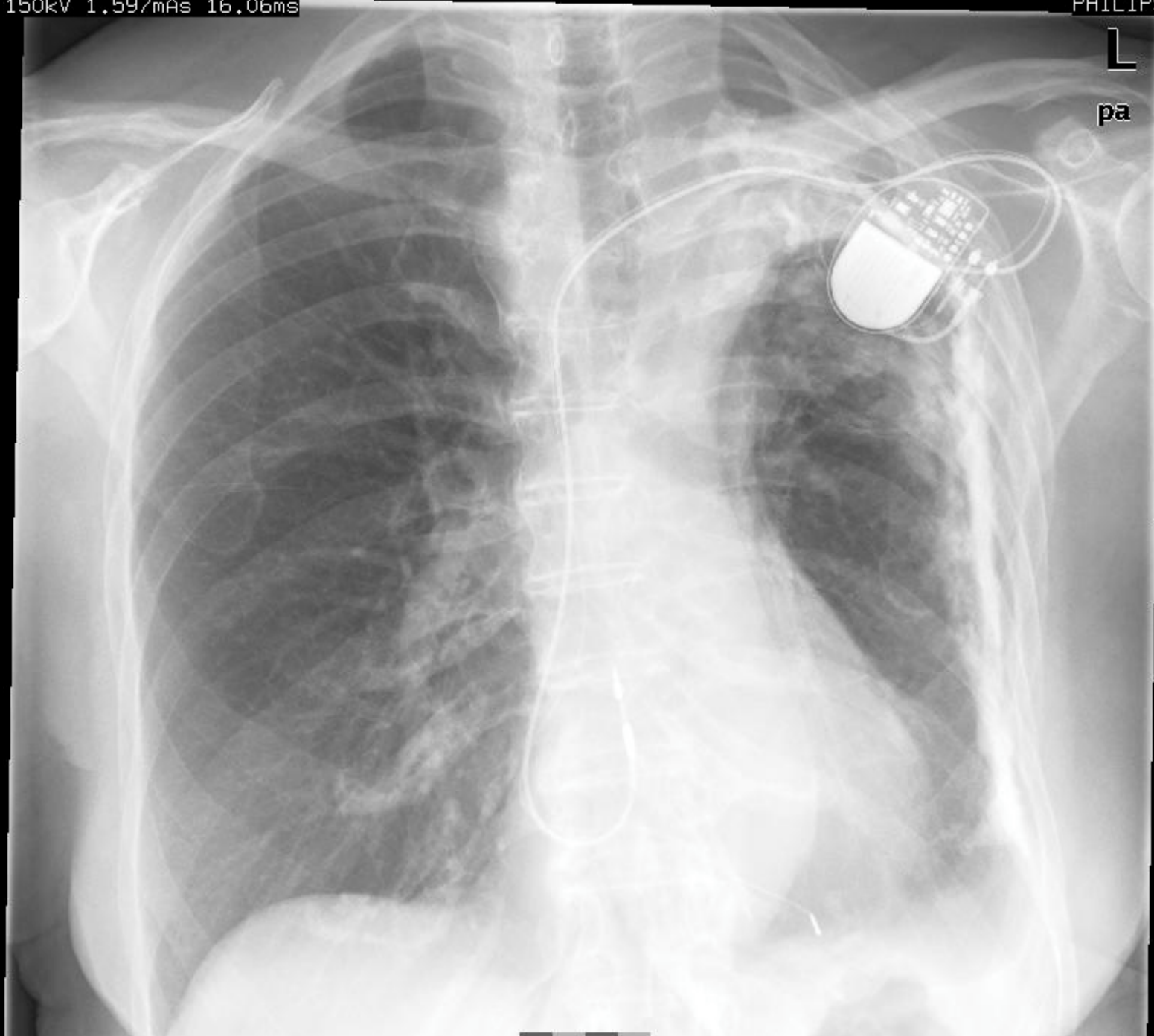


150kV 1.597mAs 16.06ms

PHILIPS

Philips

pa



0.5359cGycm2 g

4\*1cm

Pixium 4600